OCT 0 6 2003						PTO/SB/21 (08-03)
B. A.	<i>j</i>		Applic	cation Number	10/63	2,662
TRANSMITTAL			Filing	Date	Augu	st 1, 2003
FC	ORM		First N	Named Inventor	Barre	tt, Ronald W.
(to be used for all corres	spondence after i	nitial filing)	Art Ur	nit		
			Exam	iner Name		
Total Number of Pages in Submission	n This		Attorn	ey Docket Number	01993	30-003110US
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Fee Transmittal Form	n	☐ Drawin	g(s)		□ A	fter Allowance Communication to Group
Fee Attached		Licensi	ng-relate	ed Papers		ppeal Communication to Board of Appeals and Interferences
Amendment/Reply		Petition	1			ppeal Communication to Group (Appeal otice, Brief, Reply Brief)
After Final Affidavits/declaration(s)		Petition to Convert to a Provisional Application		□Р	roprietary Information	
Affidavits/decla	ration(s)	Power of Attorney, Revocation Change of Correspondence Address		☐ s	tatus Letter	
Extension of Time Ro	equest	☐ Terminal Disclaimer			ther Enclosure(s) lease identify below):	
Express Abandonme	ent Request	Request for Refund CD, Number of CD(s)		Return	Postcard, copy of one (1) cited reference	
Information Disclosus	re Statement		mber or	00(0)		
Certified Copy of Priority Document(s)		Remar	ks	The Commissioner is a Account 20-1430.	uthorize	ed to charge any additional fees to Deposit
Response to Missing Incomplete Application		-]		
Response to Mi under 37 CFR 1	•					
				ICANT, ATTORNEY,	OR AG	ENT
or _	wnsend and T		nd Crev	_		
Individual	ouglas M. Ham	ilton		Reg. No). 47,62 ———	9
Signature	1)/		***		<u>.</u>	
Date	10/01/	03				
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I hereby certify that this corresp as first class mail in an envelop	condence is being to be addressed to: Co	acsimile transr	nitted to t r Patents	he USPTO or deposited with , P.O. Box 1450, Alexandria,	the Unite	ed States Postal Service with sufficient postage 3-1450 on the date shown below.
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Attorney Docket No.: 019930-003110US

Commissioner for Patents
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Alexandria, VA 22313-1450
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TOWNSEND and TOWNSEND and CREW LLP

By: Colo M. Wartell

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Bevan Staple et al.

Application No.: 10/632,662

Filed: August 1, 2003

For: SYSTEMS AND METHODS FOR OVERCOMING STICTION USING A

LEVER

Examiner:

Art Unit:

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §1.97 and §1.98

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The references cited on attached form PTO/SB/08A and PTO/SB/08B are being called to the attention of the Examiner. In accordance with 37 CFR §1.98(d), copies of many of the references can be found in Application No. 09/898,988, filed 07/03/2001 (Attorney Docket No. 019930-003100US). All other U.S. patents are not enclosed in accordance with the Patent Office waiver issued August 5, 2003 in the Official Gazette, which states as follows:

The Office hereby waives the requirement under 37 CFR 1.98

(a)(2)(i) for submitting a copy of each cited U.S. patent and each U.S. patent application publication for all U.S. national patent

Application No.: 10/632,662

Page 2

applications filed after June 30, 2003 and for all international

applications that have entered the national stage under 35 USC 371

after June 30, 2003. See 37 CFR 1.491(b). For all patent

applications filed on or before June 30, 2003, copies of cited U.S.

patents and patent application publications are still required unless

an eIDS is filed.

In accordance with 37 CFR 1.98(a)(2), a copy of the C28, a non-patent literature

reference, is enclosed.

It is respectfully requested that the cited references be expressly considered

during the prosecution of this application, and the references be made of record therein and

appear among the "references cited" on any patent to issue therefrom.

As provided for by 37 CFR 1.97(g) and (h), no inference should be made that the

information and references cited are prior art merely because they are in this statement and no

representation is being made that a search has been conducted or that this statement encompasses

all the possible relevant information.

Applicant believes that no fee is required for submission of this statement.

However, if a fee is required, the Commissioner is authorized to deduct such fee from the

undersigned's Deposit Account No. 20-1430. Please deduct any additional fees from, or credit

any overpayment to, the above-noted Deposit Account.

Respectfully submitted,

Douglas M. Hamilton

Reg. No. 47,629

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Fax: 303-571-4321

DMH:nmb 60050606 v1

PTO/SB/08A (08-03) ubstitute for form 1440A/PTO Complete if Known FORMATION DISCLOSURE **Application Number** 10/632,662 Filing Date August 1, 2003 STATEMENT BY APPLICANT First Named Inventor Staple, Bevan Art Unit (use as many sheets as necessary) **Examiner Name** 3 of **Attorney Docket Number** Sheet 019930-003110US

			U.S. PATENT DO	CUMENTS+		
		Document Number				
Examiner Initials*	Cite No. ¹	Number Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
	A1	US-4,330,175	05-18-1982	Yohji Fujii et al.		
m:	A2	US-4,733,945	03-29-1988	Bacich		
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	A39	US-6,614,581 B2	09-02-2003	Anderson		

Examiner Signature	Date Considered	

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Kind Codes of U.S. Patent Documents at www.uspto.gov or MPEP 901.04.

Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).

For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible.

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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	C1	AKIYAMA, T. et al.; "Controlled Stepwise Motion in Polysilicon Microstructures," Journal of Microelectromechanical Systems, Vol. 2, No. 3, September 1993; pp.106-110	
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Signature	Considered	

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INFORMATION DISCLOSURE **STATEMENT BY APPLICANT**

Complete if Known Application Number 10/632,662 Filing Date August 1, 2003 First Named Inventor Staple, Bevan Art Unit Examiner Name 019930-003110US Attorney Docket Number

(use as many sheets as necessary) 3 3 Sheet of

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T 2
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	C19	SCHILLING, M. et al., "Deformation-free overgrowth of reactive ion beam etched submicron structures in InP by liquid phase epitaxy," Appl. Phys. Lett. 49 (12), 22 September 1986	
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Signature	Considered	

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